

ST13007D

HIGH VOLTAGE FAST-SWITCHING NPN POWER TRANSISTOR

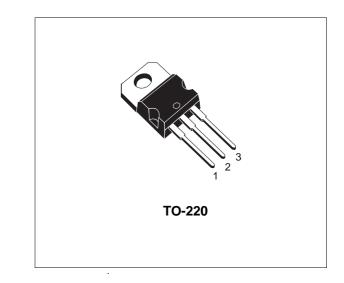
- IMPROVED SPECIFICATION:
 - LOWER LEAKAGE CURRENT
 - TIGHTER GAIN RANGE
 - DC CURRENT GAIN PRESELECTION - TIGHTER STORAGE TIME RANGE
- HIGH VOLTAGE CAPABILITY
- INTEGRATED FREE-WHEELING DIODE
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR RELIABLE OPERATION
- VERY HIGH SWITCHING SPEED
- FULLY CHARACTERIZED AT 125 °C
- LARGE RBSOA

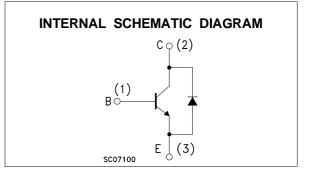
APPLICATIONS

- UP TO 120W ELECTRONIC TRANSFORMERS FOR HALOGEN LAMPS
- SWITCH MODE POWER SUPPLIES

DESCRIPTION

The device is manufactured using high voltage Multi Epitaxial Planar technology for high switching speeds and high voltage capability. It uses a Cellular Emitter structure to enhance switching speeds.





ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
VCEV	Collector-Emitter Voltage (V _{BE} = -1.5V)	700	V
VCEO	Collector-Emitter Voltage (I _B = 0)	400	V
V _{EBO}	Emitter-Base Voltage $(I_C = 0)$	9	V
Ι _C	Collector Current	8	А
I _{CM}	Collector Peak Current	16	А
IB	Base Current	4	А
I _{BM}	Base Peak Current	8	А
P _{tot}	Total Dissipation at $T_c \le 25$ °C	80	W
T _{stg}	Storage Temperature	-65 to 150	°C
Tj	Max. Operating Junction Temperature	150	°C

April 2003

THERMAL DATA

R _{thj-case}	Thermal Resistance Junction-case	Max	1.56	°C/W
$R_{thj-amb}$	Thermal Resistance Junction-ambient	Max	62.5	°C/W

ELECTRICAL CHARACTERISTICS ($T_{case} = 25 \ ^{\circ}C$ unless otherwise specified)

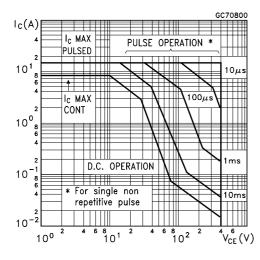
Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
ICES	Collector Cut-off Current (V _{BE} = 0)	$V_{CE} = 700 V$ $V_{CE} = 700 V$ $T_{c} = 100 °C$			10 0.5	μA mA
ICEO	Collector Cut-off Current ($I_B = 0$)	V _{CE} = 400 V			100	μA
I _{EBO}	Emitter Cut-off Current $(I_C = 0)$	$V_{EB} = 9 V$			100	μA
V _{CEO(sus)} *	Collector-Emitter Sustaining Voltage (I _B = 0)	I _C = 10 mA	400			V
V _{CE(sat)} *	Collector-Emitter Saturation Voltage				0.8 1.5 2 3	V V V V
V _{BE(sat)} *	Base-Emitter Saturation Voltage				1.2 1.6 1.5	V V V
h _{FE} *	DC Current Gain		18 8		40 25	
V _f	Diode Forward Voltage	I _C = 3 A			2.5	V
t _s t _f	INDUCTIVE LOAD Storage Time Fall Time			1.7 90	2.3 150	μs ns
ts tf	INDUCTIVE LOAD Storage Time Fall Time			2.2 150		μs ns

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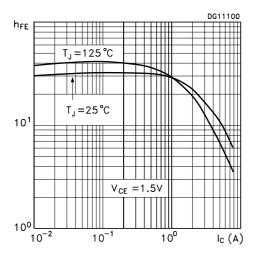
* Pulsed: Pulse duration = 300 μs, duty cycle 2 %.

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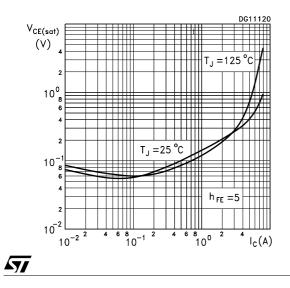
Safe Operating Area



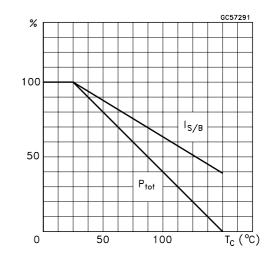
DC Current Gain



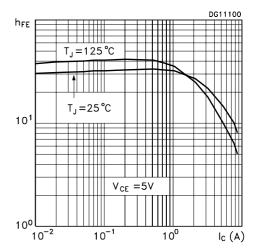
Collector Emitter Saturation Voltage



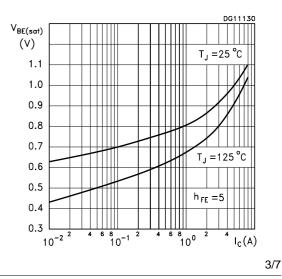
Derating Curve



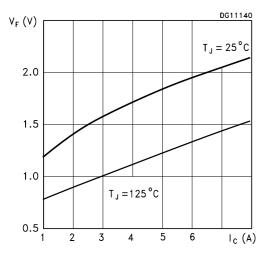
DC Current Gain



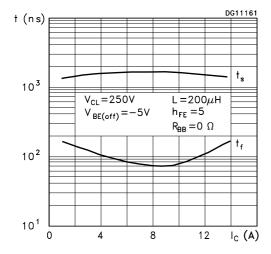




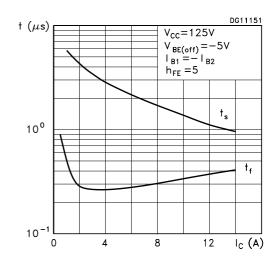
Diode Forward Voltage



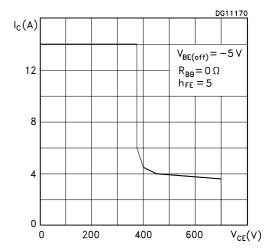
Switching Time Inductive Load



Switching Time Resistive Load







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Figure 1: Inductive Load Switching Test Circuit.

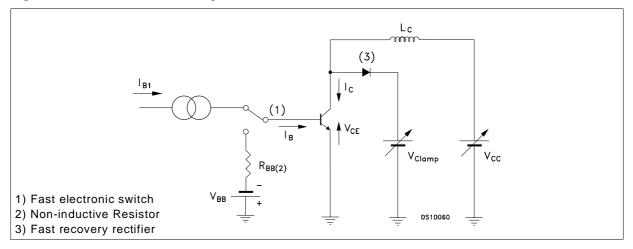
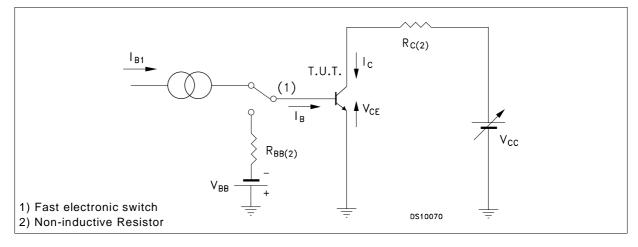
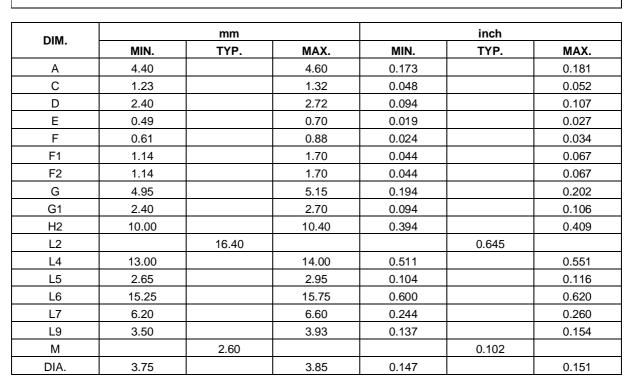


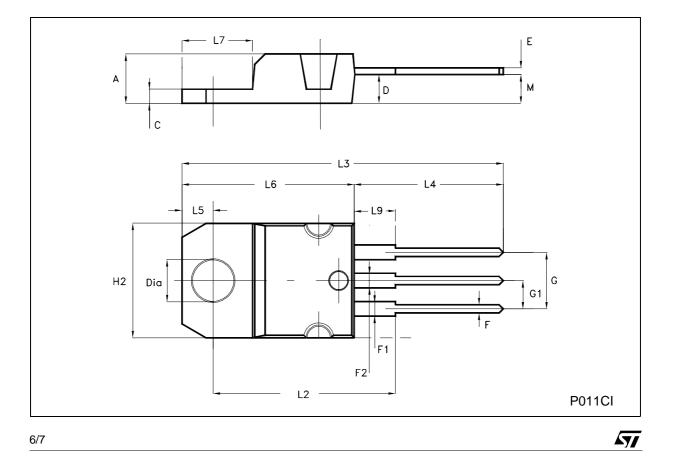
Figure 2: Resistive Load Switching Test Circuit.











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